

| ID | $R_{DS(ON)}$ (Typ) | VDSS |
|-----|--------------------|------|
| 60A | 4.6m Ω | 30V |

Applications:

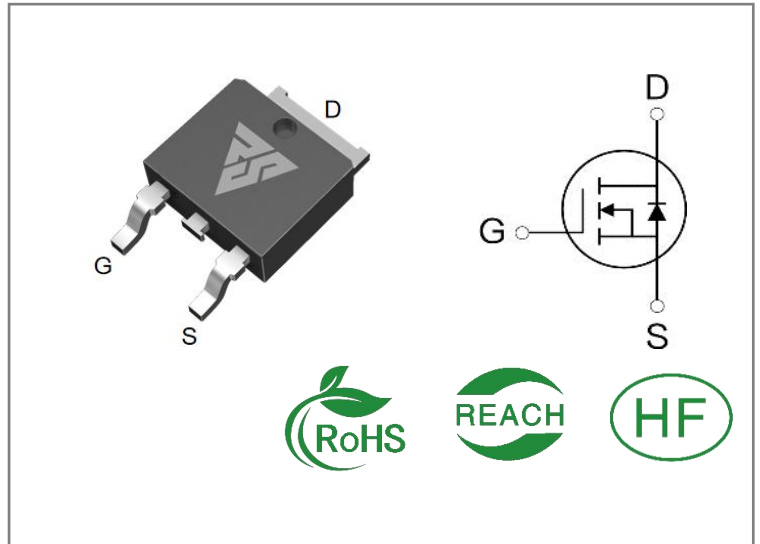
- Load Switch
- PWM Applications
- Power Managment

Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability

Ordering Information

| Part Number | Package | Marking | Packing | Qty. |
|-------------|---------|----------|-----------|----------|
| RS30N60D | T0-252 | RS30N60D | Tape&reel | 2500 PCS |


Absolute Maximun Ratings $T_c = 25^{\circ}\text{C}$ unless otherwise specified

| Symbol | Parameter | RS30N60D | Units |
|-------------|--|------------|--------------------|
| VDSS | Drain-to-Source Voltage | 30 | V |
| ID | Continuous Drain Current $T_C = 25^{\circ}\text{C}$ | 60 | A |
| ID | Continuous Drain Current $T_C = 100^{\circ}\text{C}$ | 40 | |
| IDM | Pulsed Drain Current (Note*1) | 240 | |
| PD | Power Dissipation | 50 | W |
| VGS | Gate- to- Source Voltage | ± 20 | V |
| EAS | Single Pulse Avalanche Engergy $L = 0.5\text{mH}$, $V_{DD} = 15\text{V}$, $R_G = 25\ \Omega$, $T_C = 25^{\circ}\text{C}$ | 80 | mJ |
| TL TPKG | Maximum Temperature for Soldering | 300 | $^{\circ}\text{C}$ |
| | Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds | 260 | |
| TJ and TSTG | Operating Junction and Storage Temperature Range | -55 to 150 | |

* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the " Absolute Maximum Ratings" Table may cause permanent damage to the device.

Thermal Resistance

| Symbol | Parameter | RS30N60D | Units | Test Conditions |
|---------------|----------------------|----------|-------------------------------|---|
| R θ JC | Junction-to-Case | 2.5 | $^{\circ}\text{C} / \text{W}$ | Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 1 5 0 $^{\circ}\text{C}$ |
| R θ JA | Junction-to- Ambient | 31 | | 1 cubic foot chamber,free air. |

OFF Characteristics $T_J = 25^{\circ}\text{C}$ unless otherwise specified

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|-------------------------------------|------|------|------|---------|---------------------------|
| BVDSS | Drain- to- source Breakdown Voltage | 30 | -- | -- | V | $V_{GS}=0V, I_D=250\mu A$ |
| IDSS | Drain- to- Source Leakage Current | -- | -- | 1 | μA | $V_{DS}=30V, V_{GS}=0V$ |
| IGSS | Gate- to- Source Forward Leakage | -- | -- | 100 | nA | $V_{GS}=20V, V_{DS}=0V$ |
| | Gate- to- Source Reverse Leakage | -- | -- | -100 | | $V_{GS}=-20V, V_{DS}=0V$ |

ON Characteristics $T_J = 25^{\circ}\text{C}$ unless otherwise specified

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|---------|--|------|------|------|------------|-------------------------------|
| RDS(on) | Static Drain- to- Source On-Resistance(Note*2) | -- | 4.6 | 6 | m Ω | $V_{GS}=10V, I_D=30A$ |
| | | -- | 7.5 | 9.5 | m Ω | $V_{GS}=4.5V, I_D=20A$ |
| VGS(TH) | Gate Threshold Voltage | 1.0 | 1.6 | 2.5 | V | $V_{GS}=V_{DS}, I_D=250\mu A$ |

Resistive Switching Characteristics Essentially independent of operating temperature

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|---------|----------------------|------|------|------|-------|--|
| td(ON) | Turn- on Delay Time | -- | 7 | -- | nS | $V_{DS}=15V$ $I_D=30A$ $R_G=3\Omega$ |
| trise | Rise Time | -- | 14 | -- | | |
| td(OFF) | Turn- OFF Delay Time | -- | 33 | -- | | |
| tfall | Fall Time | -- | 11 | -- | | |

Dynamic Characteristics Essentially independent of operating temperature

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|---------------------------------|------|------|------|-------|-------------------------------|
| Ciss | Input Capacitance | -- | 1780 | -- | pF | VGS=0V VDS=15V f=1.0MHz |
| Coss | Output Capacitance | -- | 220 | -- | | |
| Crss | Reverse Transfer Capacitance | -- | 178 | -- | | |
| Qg | Total Gate Charge | -- | 34 | -- | nC | VDS=15V ID=30A VGS=10V |
| Qgs | Gate- to- Source Charge | -- | 7 | -- | | |
| Qgd | Gate-to-Drain(" Miller") Charge | -- | 7.5 | -- | | |

Source- Drain Diode Characteristics

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|---------------------------|------|------|------|-------|-----------------------------------|
| IS | Continuous Source Current | -- | -- | 60 | A | Integral pn- diode in MOSFET |
| ISM | Maximum Pulsed Current | -- | -- | 240 | A | |
| VSD | Diode Forward Voltage | -- | -- | 1.2 | V | IS=30A,VGS=0V |
| trr | Reverse Recovery Time | -- | 10 | -- | nS | VGS=0V IS=20A di/dt=100A/μs |
| Qrr | Reverse Recovery Charge | -- | 1.7 | -- | nC | |

Notes:

- * 1. Repetitive rating, pulse width limited by maximum junction temperature.
- * 2. Pulse Test: Pulse width $\leq 300\mu s$, Duty Cycle $\leq 0.5\%$

Typical Feature Curve

Figure 1: Output Characteristics

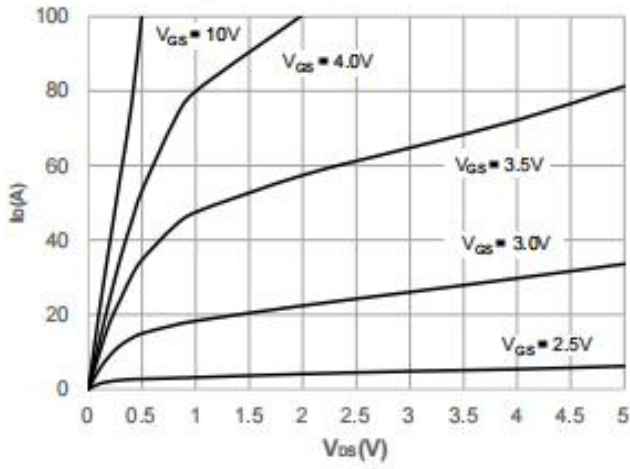


Figure 2: Typical Transfer Characteristics

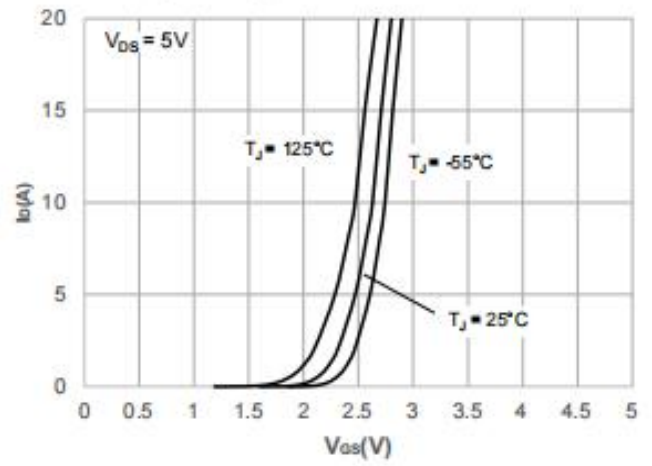


Figure 3: On-resistance vs. Drain Current

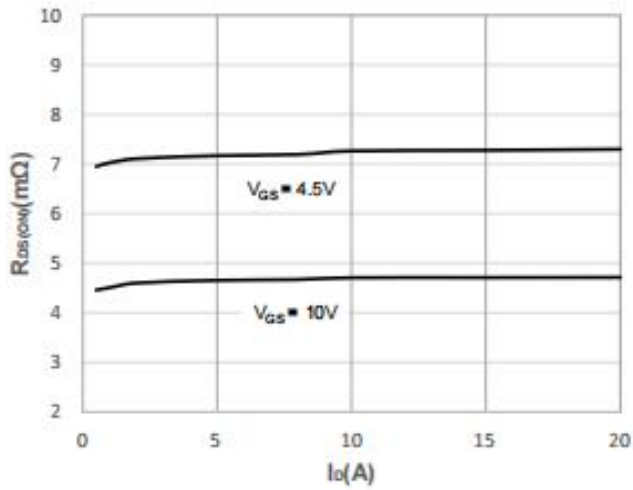


Figure 4: Body Diode Characteristics

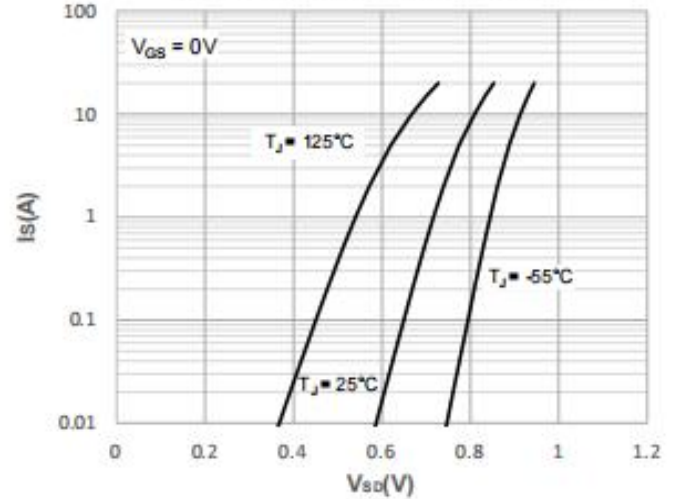


Figure 5: Gate Charge Characteristics

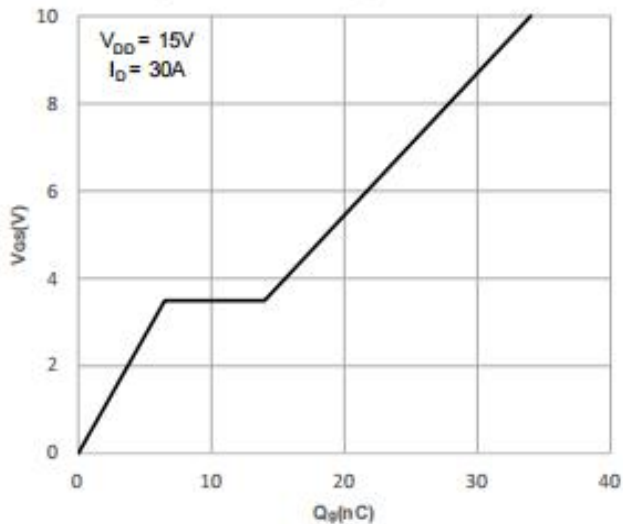


Figure 6: Capacitance Characteristics

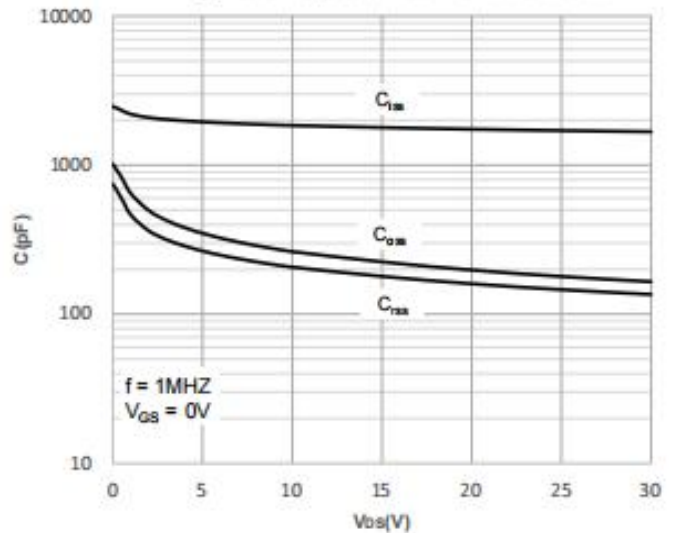


Figure 7: Normalized Breakdown voltage vs. Junction Temperature

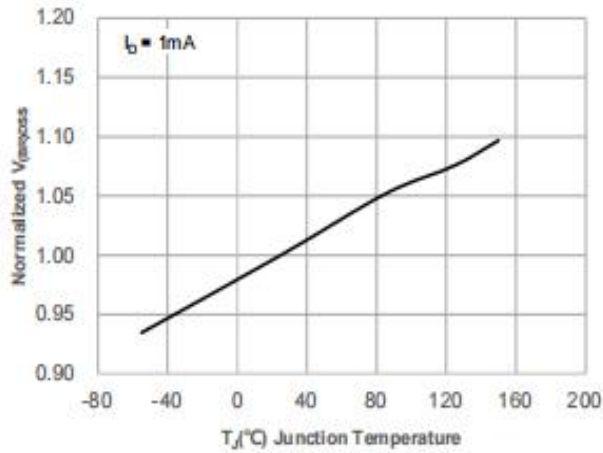


Figure 8: Normalized on Resistance vs. Junction Temperature

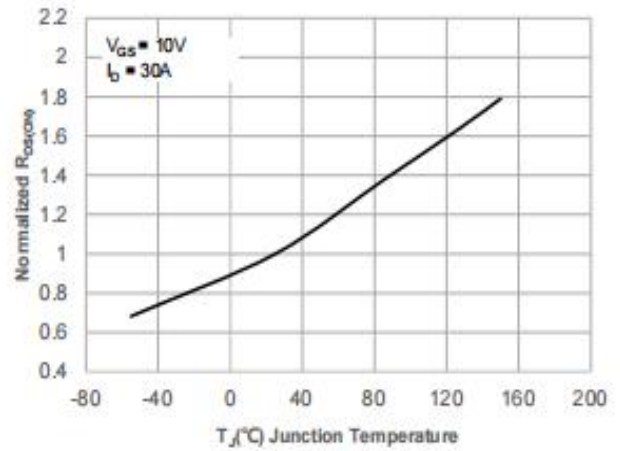


Figure 9: Maximum Safe Operating Area

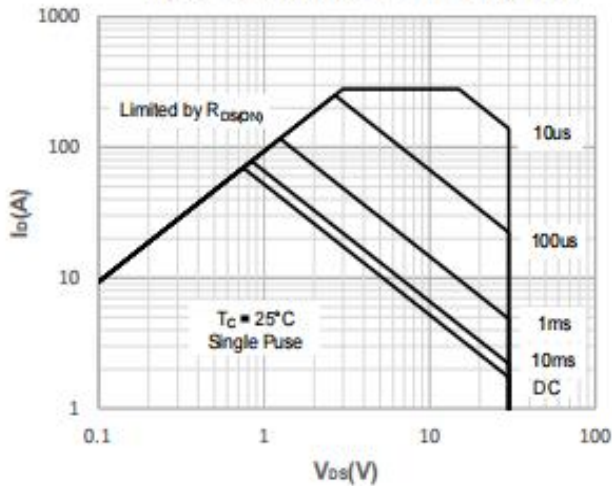


Figure 10: Maximum Continuous Drian Current vs. Case Temperature

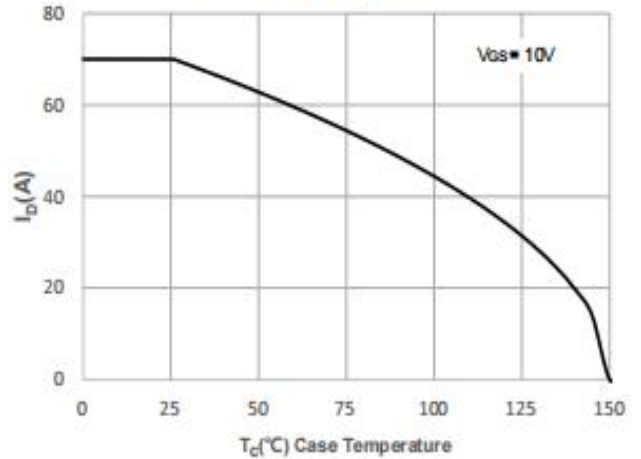


Figure 11: Normalized Maximum Transient Thermal Impedance

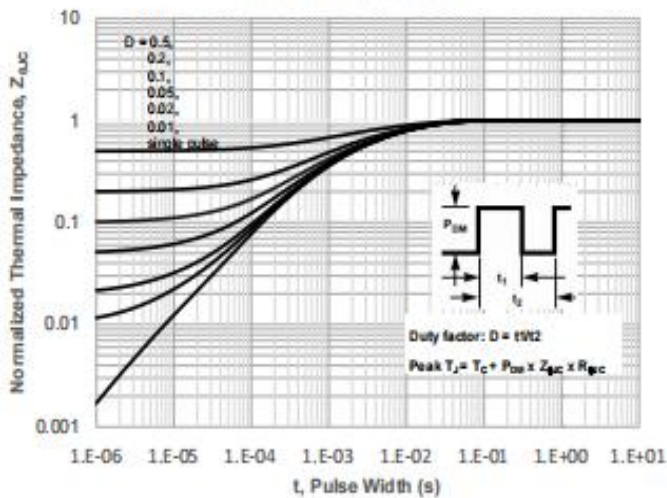
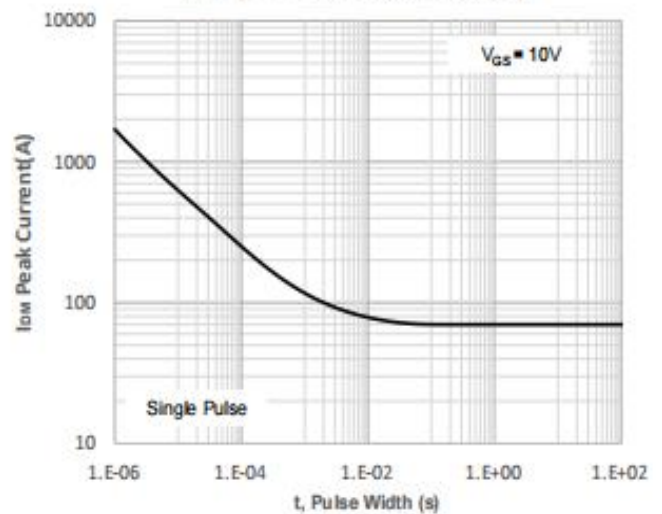


Figure 12: Peak Current Capacity



Test Circuits and Waveforms

Figure A: Gate Charge Test Circuit and Waveform

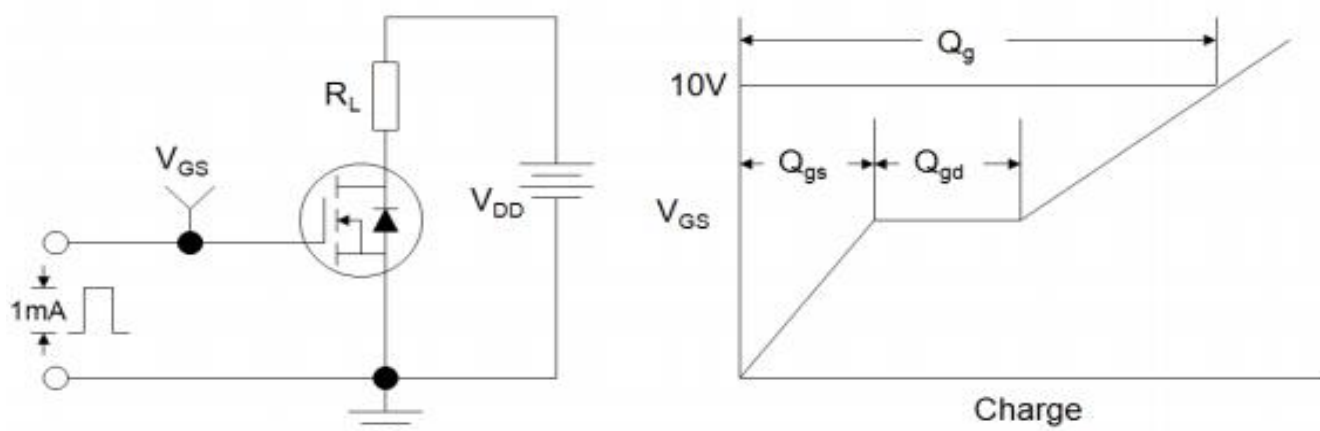


Figure B: Resistive Switching Test Circuit and Waveform

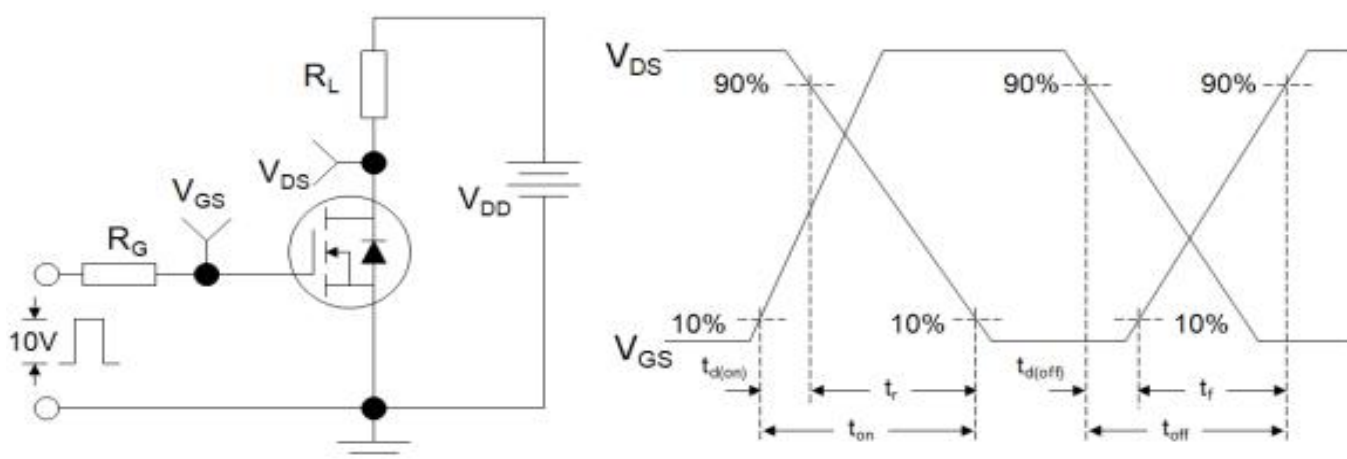
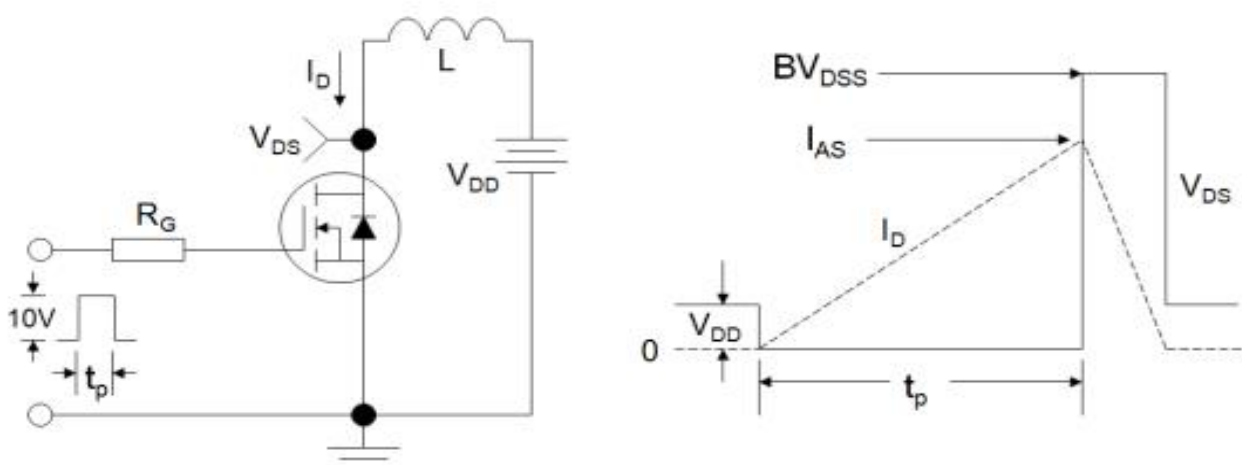
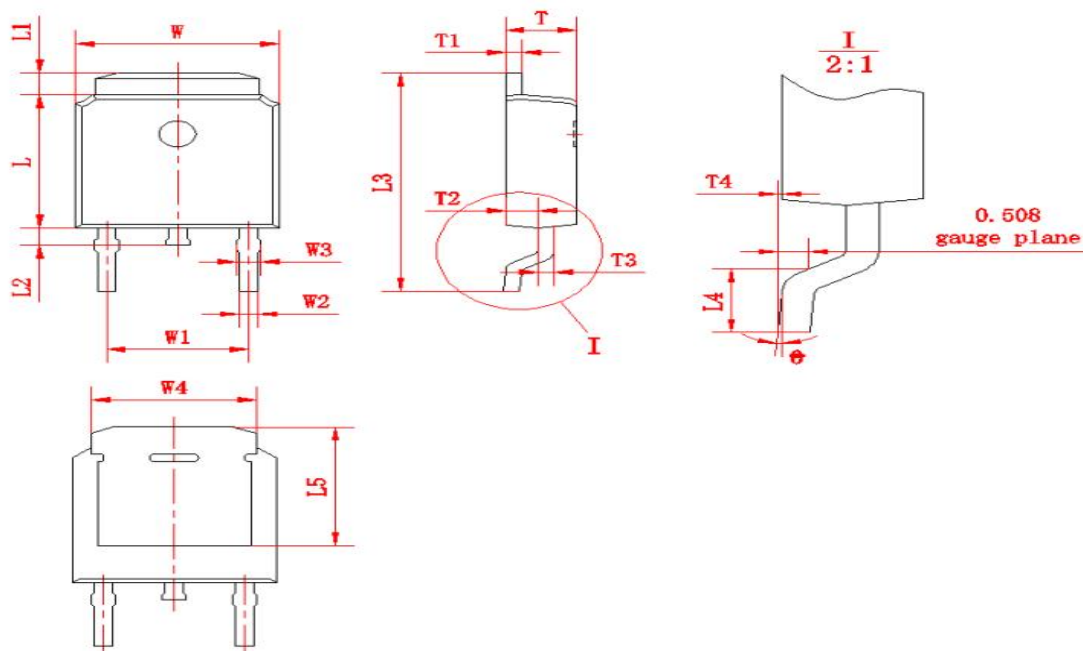


Figure C: Unclamped Inductive Switching Test Circuit and Waveform



Package outline drawing(TO-252 Unit: mm)



| 符号 | 尺寸 | | 符号 | 尺寸 | | 符号 | 尺寸 | |
|----|---------|------|----|--------|-------|----|------|------|
| | Min | Max | | Min | Max | | Min | Max |
| W | 6.50 | 6.70 | L1 | 0.80 | 1.20 | T1 | 0.48 | 0.58 |
| W1 | (4.572) | | L2 | 0.60 | 1.00 | T2 | 0.95 | 1.15 |
| W2 | 0.6 | 0.8 | L3 | 9.70 | 10.30 | T3 | 0.48 | 0.58 |
| W3 | 0.68 | 0.88 | L4 | 1.30 | 1.70 | T4 | 0.00 | 0.12 |
| W4 | (5.3) | | L5 | (5.20) | | 0 | 0 | 8 |
| L | 6.00 | 6.20 | T | 2.20 | 2.40 | | | |

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